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INFORMATION DISCLOSURE STATEMENT						.						
(Use several sheets if necessary)				APPLICANTS Peter Jan NIEUWENHUIZEN et al.								
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Date: February 22, 2005

ATTY DOCKET NO. APPLICATION NO. US Dept. of Commerce Form PTO-1449 PATENT & TRADEMARK OFFICE 121200 10/508.970 (REV. 8-83) INFORMATION DISCLOSURE STATEMENT APPLICANTS Peter Jan NIEUWENHUIZEN et al. (Use several sheets if necessary) FILING DATE November 15, 2004 **GROUP 1723** U.S. PATENT DOCUMENTS SUB **EXAMINER CLASS CLASS DOCUMENT NUMBER** DATE NAME **INITIAL O**)S.D. 11/21/1978 DeBERRY 1) 4,126,529 09/16/1986 HARKNESS et al. 2) 4,612,175 CHANG et al. 3) 4,732,744 03/2/1988 03/20/1990 **GRINSTEAD** 4) 4,910,002 12/01/1992 **GALLUP** 5) 5,167,834 CHANG 12/06/1994 6) 5,370,849 7) 04/06/1999 BUISMAN et al. 5,891,408 FOREIGN PATENT DOCUMENTS SUB **CLASS CLASS** DATE COUNTRY **DOCUMENT NUMBER** 11/09/1977 **JAPAN** /S.D./ 8) JP A 52-133876 w/ abstract \ **JAPAN** 10/31/1977 9) JP A 52-129677 w/ abstract 02/09/1978 **JAPAN** JP A 53-14678 w/ abstract 10) **GERMANY** 02/08/1979 11) DE 28 33 440 A1 w/ abstract 1 08/29/1979 **JAPAN** JP A 54-110166 w/ abstract 12) 13) DE 35 04 157 A w/ abstract 1 08/07/1986 GERMANY **WIPO** 10/09/1986 14) WO 86/05709 A1 w/ abstract ... 02/19/1987 **GERMANY** 15) DE 35 28 971 A1 w abstract GERMANY 16) DE 35 31 397 A1 w/ abstract 03/05/1987 **GERMANY** DE 35 31 398 A1 w/ abstract 03/05/1987 17) WO 87/02269 A1 w/ abstract 04/23/1987 WIPO 18) 02/25/1988 **GERMANY** 19) DE 36 28 402 A1 w/ abstract 08/25/1988 **GERMANY** 20) DE 37 04 516 A1 w/ abstract 21) WO 91/15591 A1 w/ abstract 10/17/1991 WIPO 12/08/1994 WIPO 22) WO 94/28464 A1 w/ abstract \ 12/22/1994 GERMANY 23) DE 43 20 070 A w/ abstract \ 02/25/1996 **CANADA** 24) CA 2,130,767 A1 10/03/1996 WIPO 25) WO 96/30299 A1 09/29/1999 **EUROPE** EP 0 945 408 B 26) **EUROPE** 27) EP 0 808 210 B1 11/26/1997 OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.) Schaep et al., "Analysis of the salt Retention of Nanofiltration membranes using the Donnan-Steric Partitioning Pore 28) /S.D./ Model," Separation Science and Technology, Vol. 34, No. 15, pp. 3009-3030, 1999 /Shanta Doe/ DATE CONSIDERED 10/12/2007 **EXAMINER** Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Examiner:

Date: July 21, 2005

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